# 2SD2457

# Silicon NPN epitaxial planar type

### For low-frequency output amplification

### ■ Features

- High collector-emitter voltage (Base open) V<sub>CEO</sub>
- Low collector power dissipation P<sub>C</sub>
- Mini Power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing.

### ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	50	V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	40	V
Emitter-base voltage (Collector open)	$V_{EBO}$	5	V
Collector current	$I_C$	1.5	A
Peak collector current	I <sub>CP</sub>	3	A
Collector power dissipation *	P <sub>C</sub>	1	W
Junction temperature	Tj	150	°C
Storage temperature	T <sub>stg</sub>	-55 to +150	°C

Note) \*: Printed circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion

# Unit: mm 4.5±0.1 1.

Marking Symbol: 1Y

## ■ Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions S	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	$V_{CBO}$	$I_C = 1 \text{ mA}, I_E = 0$	50			V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_C = 2 \text{ mA}, I_B = 0$	40			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = 20 \text{ V}, I_{B} = 0$			1	μΑ
Collector-emitter cutoff current (Base open)	$I_{CEO}$	$V_{CE} = 10 \text{ V}, I_{B} = 0$			100	μΑ
Emitter-base cutoff current (Collector open)	I <sub>EBO</sub>	$V_{EB} = 5 \text{ V}, I_{E} = 0$			10	μΑ
Forward current transfer ratio *1,2	C RPE	$V_{CE} = 5 \text{ V}, I_{C} = 1 \text{ A}$	80	120	220	_
Collector-emitter saturation voltage *1	V <sub>CE(sat)</sub>	$I_C = 1.5 \text{ A}, I_B = 0.15 \text{ A}$			1.0	V
Base-emitter saturation voltage *	V <sub>BE(sat)</sub>	$I_C = 2 A, I_B = 0.2 A$			1.5	V
Transition frequency *1	$f_T$	$V_{CB} = 5 \text{ V}, I_{E} = -0.5 \text{ A}, f = 200 \text{ MHz}$		150		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = 20 \text{ V}, I_{E} = 0, f = 1 \text{ MHz}$		45		pF
(Common base, input open circuited)						

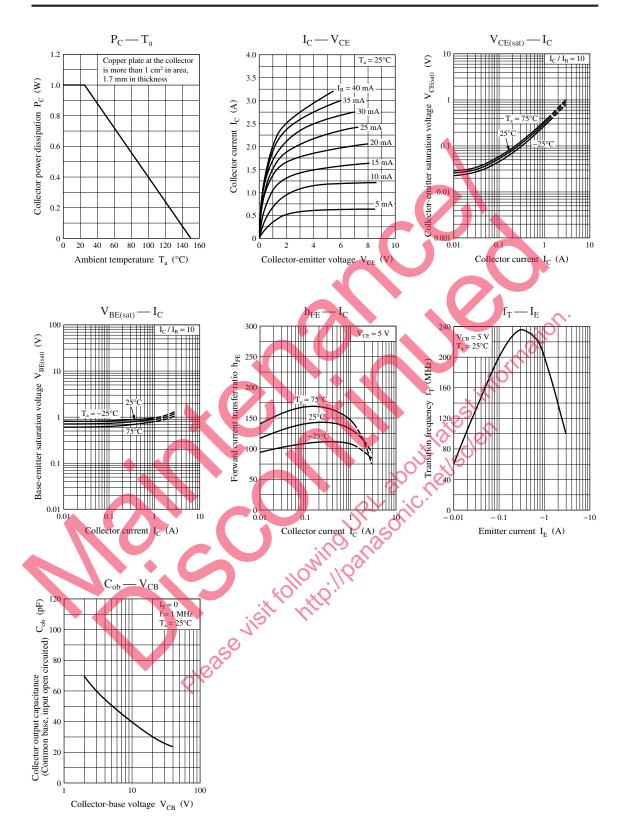
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*1: Pulse measurement

\*2: Rank classification

Rank	Q	R
$h_{FE}$	80 to 160	120 to 220

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